

ABSOLUTE MAXIMUM RATINGS*

Voltage on any pin relative to V _{SS}	-0.5V to 7.0V
Operating Temperature t _A (Ambient)	
Commercial	0°C to +70°C
Industrial	-40°C to +85°C
Storage Temperature, Plastic	-55°C to +125°C
Power Dissipation	2.5 Watts
Output Current	20 mA
Junction Temperature, t _J	-175°C

*Stress greater than those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions greater than those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect reliability.

RECOMMENDED DC OPERATING CONDITIONS

Parameter	Sym	Min	Typ	Max	Units
Supply Voltage	V _{CC}	3.135	3.3	3.465	V
Supply Voltage	V _{SS}	0	0	0	V
Input High Voltage	V _{IH}	2.2	--	V _{CC} + 0.3	V
Input Low Voltage	V _{IL}	-0.3	--	+0.8	V

CAPACITANCE

(f=1.0MHz, V_{IN}=V_{CC} or V_{SS})

Parameter	Sym	Max	Unit
Address Lines	CI	30	pF
Data Lines	CD/Q	10	pF
Chip Enable Line	E0-3	8	pF
Write & Output Enable Line	W#, G#	30	pF

TRUTH TABLE

E#	W#	G#	Mode	Output	Power
H	X	X	Standby	HIGH Z	I _{CC2} , I _{CC3}
L	H	H	Output Deselect	HIGH Z	I _{CC1}
L	H	L	Read	D _{OUT}	I _{CC1}
L	L	X	Write	D _{IN}	I _{CC1}

DC ELECTRICAL CHARACTERISTICS

(V_{CC}= 3.3V, t_A = 25°C)

Parameter	Sym	Conditions	12 & 15			17 & 20			Units
			Min	Typ	Max	Min	Typ	Max	
Operating Power Supply Current	I _{CC1}	W# = V _{IL} , I/O = 0mA, Min Cycle	--	440	800	--	440	640	mA
Standby (TTL) Power Supply Current	I _{CC2}	E# ≥ V _{IH} , V _{IN} ≤ V _{IL} or V _{IN} ≥ V _{IH}	--	100	300	--	100	200	mA
Full Standby Power CMOS Supply Current	I _{CC3}	E# ≥ V _{CC} -0.2V V _{IN} ≥ V _{CC} -0.2V or V _{IN} ≤ 0.2V	--	60	80	--	60	100	mA
Input Leakage Current	I _{LI}	V _{IN} = 0V to V _{CC}	--	--	±20	--	--	±10	µA
Output Leakage Current	I _{LO}	V I/O = 0V TO V _{CC}	--	--	±20	--	--	±10	µA
Output High Voltage	V _{OH}	I _{OH} = -4.0mA	2.4	--	--	2.4	--	--	V
Output Low Voltage	V _{OL}	I _{OL} = 4.0mA	--	--	0.4	--	--	0.4	V

AC TEST CONDITIONS

Input Pulse Levels	V _{SS} to 3.0V
Input Rise and Fall Times	5ns
Input and Output Timing Levels	1.5V
Output Load	Figure 1

Note: For t_{EHQZ}, t_{GHQZ} and t_{WLQZ}, CL = 5pF, Figure 2

AC CHARACTERISTICS READ CYCLE

(V_{CC} = 3.3V, V_{SS} = 0V, t_A = 0°C to -70°C)

Parameter	Symbol		12ns		15ns		17ns		20ns		Units
	JEDEC	Alt.	Min	Max	Min	Max	Min	Max	Min	Max	
Read Cycle Time	t _{AVAV}	t _{RC}	12		15		17		20		ns
Address Access Time	t _{AVQV}	t _{AA}		12		15		17		20	ns
Chip Enable Access	t _{ELQV}	t _{ACS}		10		12		15		20	ns
Chip Enable to Output in Low Z (1)	t _{ELQX}	t _{CLZ}	3		3		3		3		ns
Chip Disable to Output in High Z (1)	t _{EHQZ}	t _{CHZ}		6		7		8		9	ns
Output Hold from Address Change	t _{AVQX}	t _{OH}	3		3		3		3		ns
Output Enable to Output Valid	t _{GLQV}	t _{OE}		6		7		8		9	ns
Output Enable to Output in Low Z (1)	t _{GLQX}	t _{OLZ}	3		3		3		3		ns
Output Disable to Output in High (1)	t _{GHQZ}	t _{OHZ}		6		7		8		9	ns

NOTE: 1. Parameter is guaranteed by design but not tested.

AC CHARACTERISTICS WRITE CYCLE

(V_{CC} = 3.3V, V_{SS} = 0V, t_A = 0°C to -70°C)

Parameter	Symbol		12ns		15ns		17ns		20ns		Units
	JEDEC	Alt.	Min	Max	Min	Max	Min	Max	Min	Max	
Write Cycle Time	t _{AVAV}	t _{WC}	12		15		17		20		ns
Chip Enable to End of Write	t _{ELWH}	t _{CW}	8		10		11		12		ns
	t _{ELEH}	t _{CW}	8		10		11		12		ns
Address Setup Time	t _{AVWL}	t _{AS}	0		0		0		0		ns
	t _{AVEL}	t _{AS}	0		0		0		0		ns
Address Valid to End of Write	t _{AVWH}	t _{AW}	8		10		11		12		ns
	t _{AEH}	t _{AW}	8		10		11		12		ns
Write Pulse Width	t _{WLWH}	t _{WP}	8		10		11		12		ns
	t _{ELEH}	t _{WP}	8		10		11		12		ns
Write Recovery Time	t _{WHAX}	t _{WR}	0		0		0		0		ns
	t _{EHAX}	t _{WR}	0		0		0		0		ns
Data Hold Time	t _{WHDX}	t _{DH}	0		0		0		0		ns
	t _{EHDX}	t _{DH}	0		0		0		0		ns
Write to Output in High Z (1)	t _{WLQZ}	t _{WHZ}	0	6	0	7	0	8	0	9	ns
Data to Write Time	t _{DVWH}	t _{DW}	6		7		8		9		ns
	t _{DVEH}	t _{DW}	6		7		8		9		ns
Output Active from End of Write (1)	t _{WHQX}	t _{WLZ}	3		3		3		3		ns

NOTE: 1. Parameter guaranteed, but not tested.

FIGURE 2 – TIMING WAVEFRONT – READ CYCLE

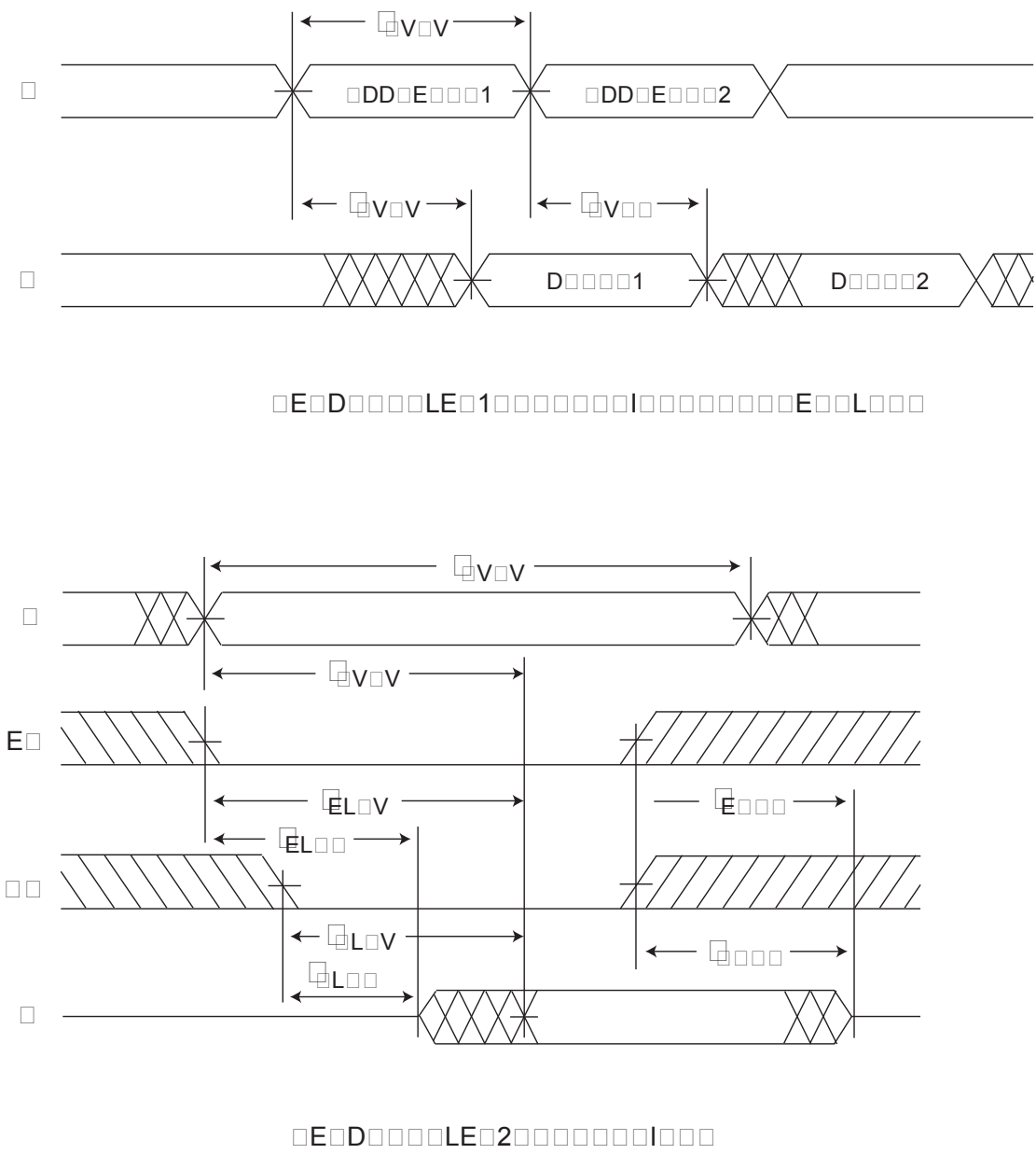


FIGURE 3 – WRITE CYCLE – W# CONTROLLED

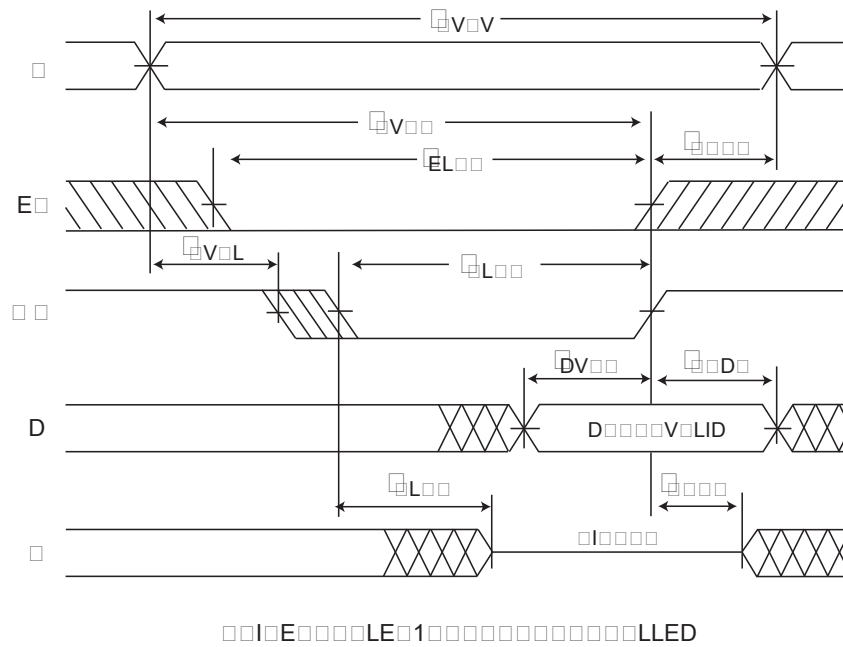
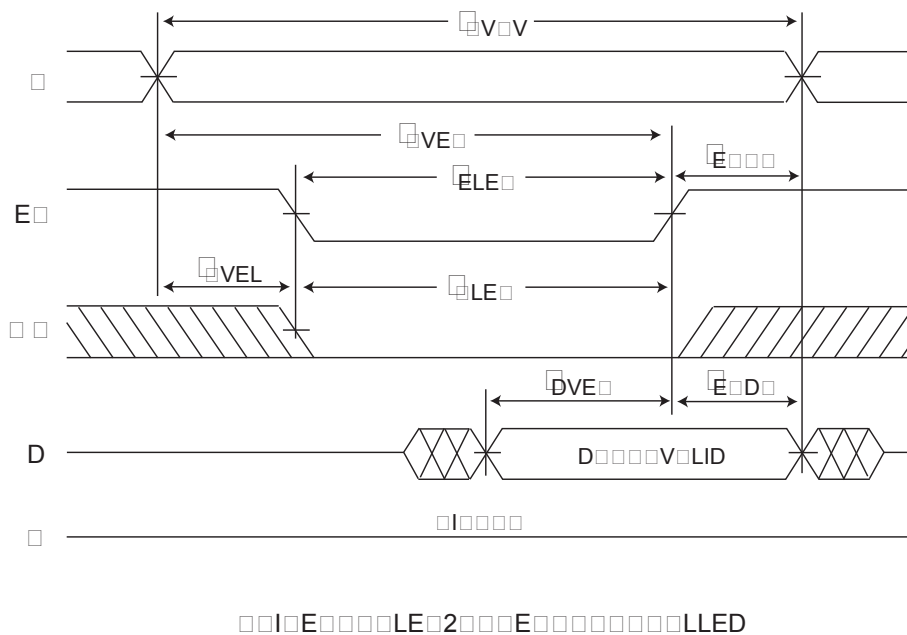


FIGURE 4 – WRITE CYCLE – E# CONTROLLED



ORDERING INFORMATION

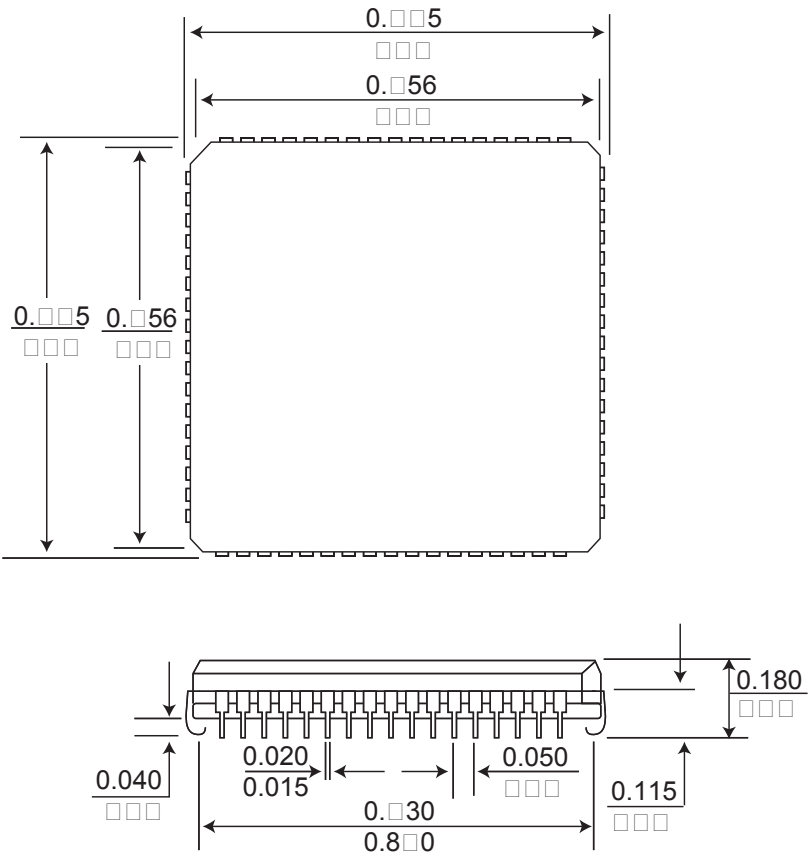
Commercial Temperature Range (0°C to +70°C)

Part Number	Speed (ns)	Package No.
EDI8L32512V12AC	12	99
EDI8L32512V15AC	15	99
EDI8L32512V17AC	17	99
EDI8L32512V20AC	20	99
EDI8L32512V25AC	25	99

Industrial Temperature Range (-40°C to +85°C)

Part Number	Speed (ns)	Package No.
EDI8L32512V15AI	15	99
EDI8L32512V17AI	17	99
EDI8L32512V20AI	20	99
EDI8L32512V25AI	25	99

PACKAGE 99" 68 LEAD PLCC JEDEC MO-47AE



Coplanarity (lowest lead to highest lead 0.004 max)

ALL DIMENSIONS ARE IN INCHES

FIGURE 5 – INTERFACING THE TEXAS INSTRUMENTS TMS 320LC32 WITH THE EDI8L32512V (512K X 32)

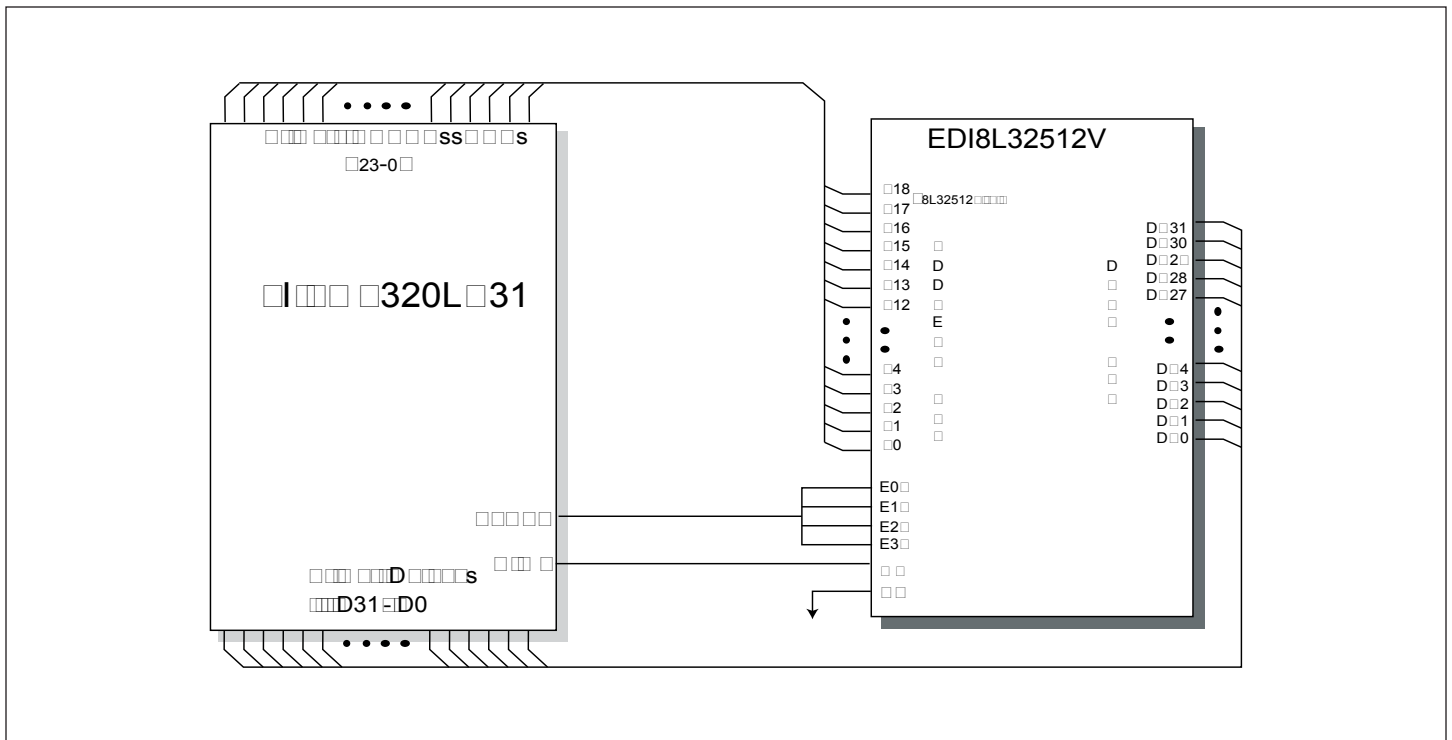


FIGURE 6 – INTERFACING THE ANALOG SHARC DSP WITH THE EDI8L32512V (512K X 32 ARRAY).

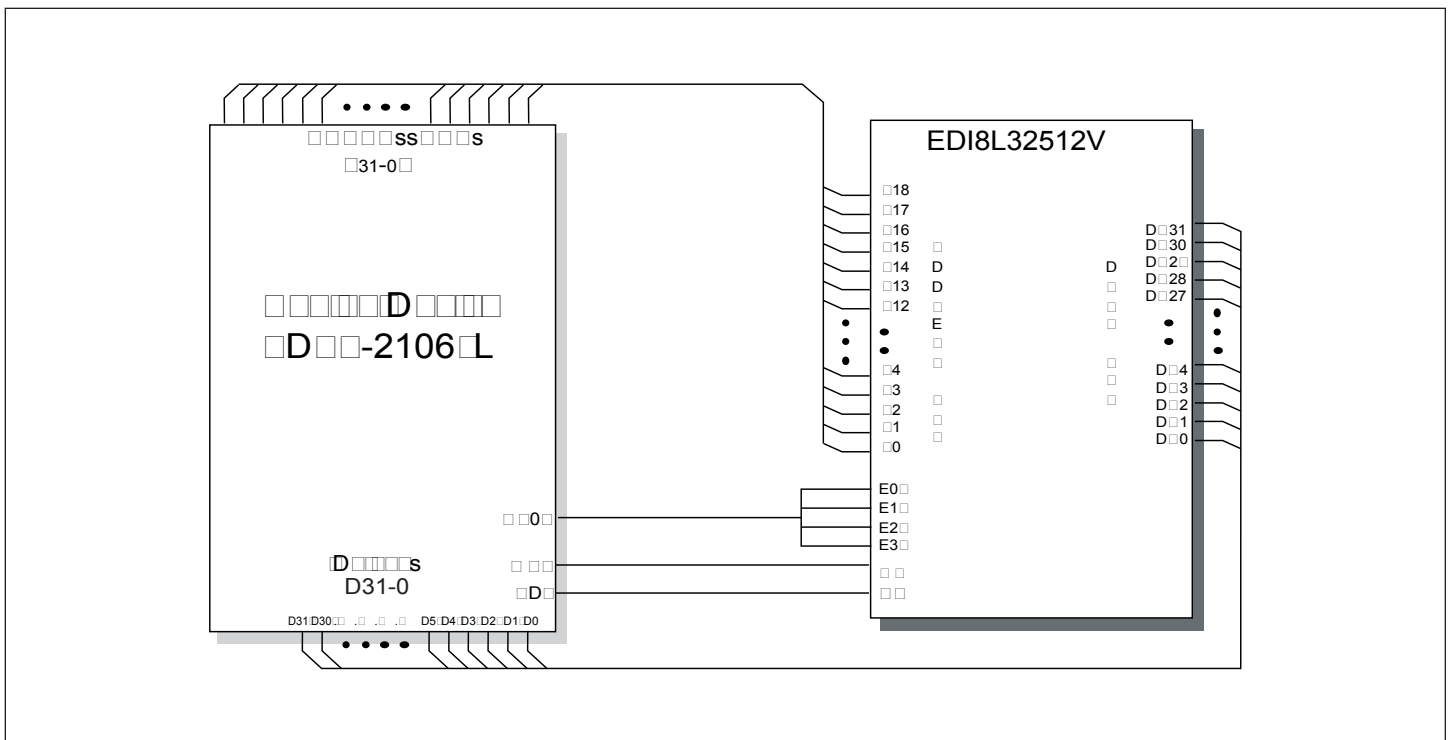


FIGURE 7 – INTERFACING THE ANALOG SHARC DSP WITH THE EDI8L32512V (1M X 48 ARRAY)

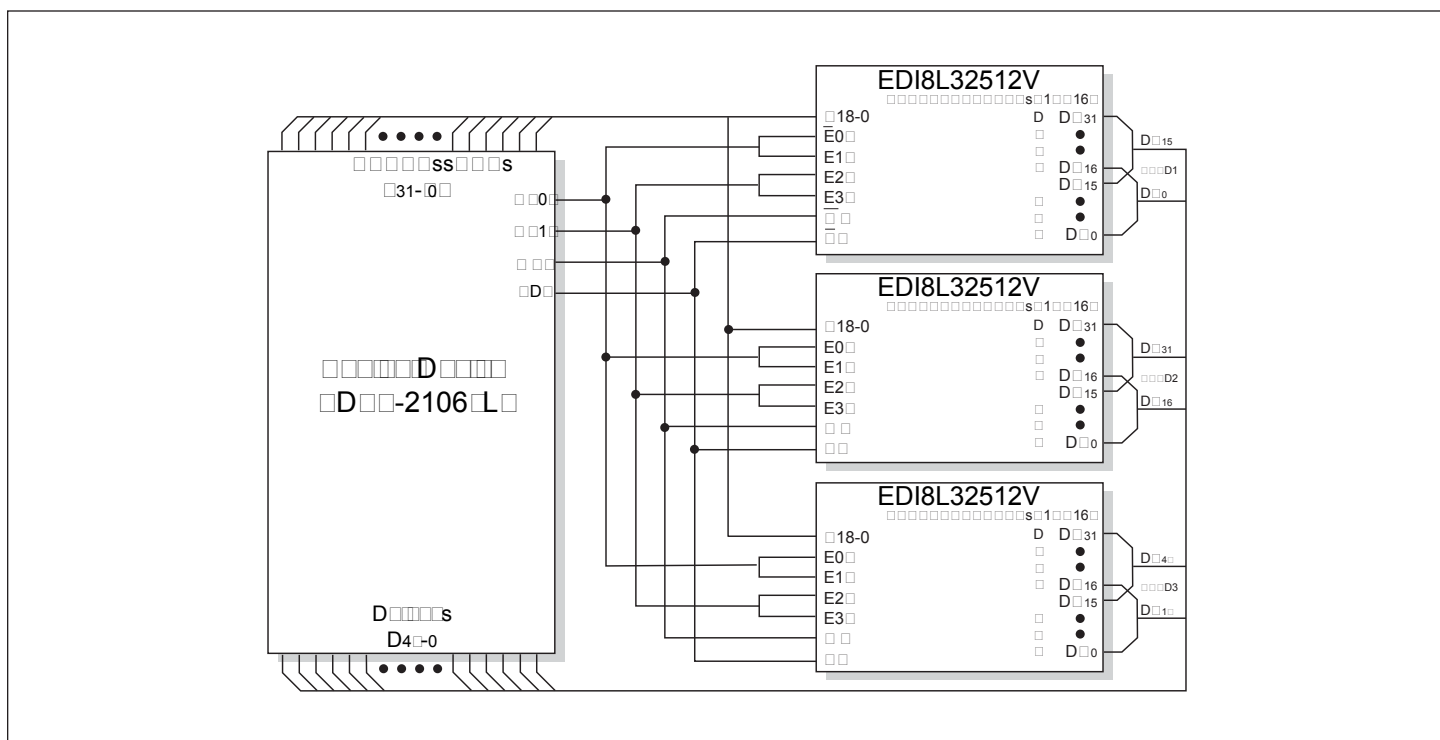
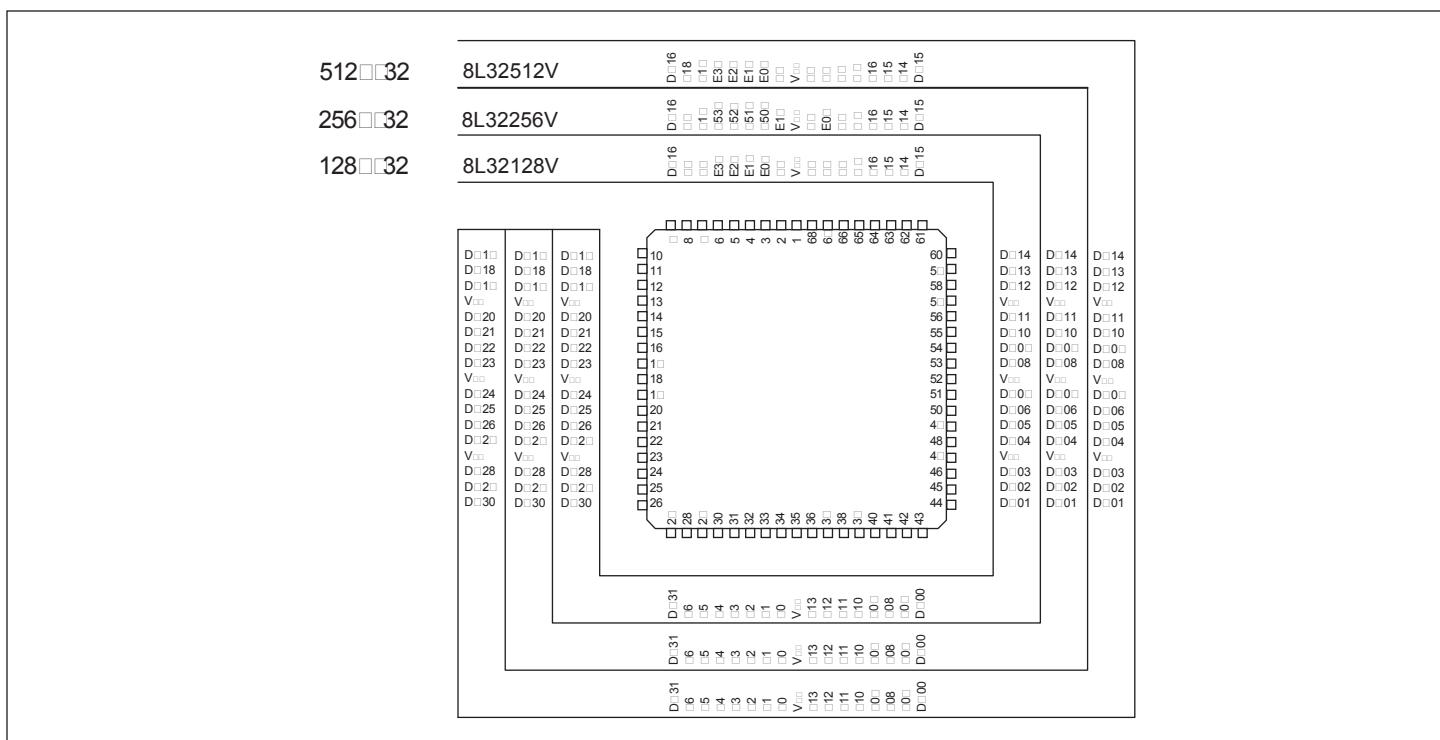


FIGURE 8 – MCM-L UPGRADE PATH



Document Title

512Kx32 SRAM Module.3.3V

Revision History

Rev #	History	Release Date	Status
Rev 5	Changes (Pg. 1-9) 5.1 Change document layout from White Electronic Designs to Microsemi 5.2 Add document Revision History page	May 2011	Final
Rev 6	Changes (Pg. All) (ECN 10156) 6.1 Change document layout from Microsemi to Mercury Systems	August 2016	Final